



# ARFTG 76<sup>th</sup> Microwave Measurement Symposium Millimeter-wave Measurements and Modeling

Clearwater Beach Marriott Suites on Sand Key, Clearwater Beach, FL.

November 30<sup>th</sup> – December 3<sup>rd</sup> 2010

[www.arftg.org](http://www.arftg.org)

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## FIRST CALL FOR PAPERS

ARFTG will hold its 76<sup>th</sup> Microwave Measurement Symposium at the Clearwater Beach Marriott Suites on Sand Key in Clearwater Beach, Florida November 30<sup>th</sup> – December 3<sup>rd</sup> 2010. The main themes of this conference are millimeter-wave and submillimeter-wave measurements and modeling.

Technical papers describing original work in the areas of measurement and analysis in these higher frequency bands are solicited. Topics of particular interest include:

- On-wafer calibration and verification issues
- Higher frequency device measurements for modeling (linear and non-linear)
- Millimeter-wave waveguide and coaxial metrology
- System-level measurements (microwave, millimeter-wave, and THz bands)
- Antenna measurements
- Other areas of rf, microwave and/or millimeter wave measurement

## DEADLINES

**September 10<sup>th</sup> 2010** Electronic Abstract/Summary due in Adobe pdf format, to:  
[http://www.mtt-tpms.org/symposia\\_v6/ARFTG\\_Fall/start.html](http://www.mtt-tpms.org/symposia_v6/ARFTG_Fall/start.html)

**October 18<sup>th</sup> 2010** Publication-ready paper due in pdf format.

Paper acceptance and classification will be communicated by **September 27<sup>th</sup> 2010**.

Instructions for authors can be found on the ARFTG web-site at  
[http://www.arftg.org/instructions\\_for\\_authors.html](http://www.arftg.org/instructions_for_authors.html).

## NIST/ARFTG MEASUREMENT SHORT COURSE

For more information about our practical measurement tutorial, contact Dominique Schreurs ([dominique.schreurs@esat.kuleuven.be](mailto:dominique.schreurs@esat.kuleuven.be) +32-16-321821). This 1.5 day short course will include topics specific to the conference theme. Additional topics may include:

Microwave measurement overview, circuit theory, VNA, interconnects and IC test fixtures and probing, RF connectors, on-wafer measurement, power, thermal noise, phase noise, uncertainty analysis, digital modulation, time-domain network analysis, overview of wireless test instrumentation and measurement, introduction to nonlinear measurement.

## MEASUREMENT WORKSHOP

For more information about our very successful measurement workshops, please contact Jean-Pierre Teyssier ([teyssier@brive.unilim.fr](mailto:teyssier@brive.unilim.fr)). Topics may include:

Nonlinear Device Measurement – presentations from acknowledged leaders in the field covering passive and active load-pull, waveform engineering, large signal network analysis, and other RF system linearity measurement techniques, Multiport/Differential Measurement for Signal Integrity, Measurement assurance when using modern VNAs

## EXHIBITS

The 76<sup>th</sup> ARFTG Conference also offers an outstanding exhibition opportunity. Please contact our Exhibits Chair directly for further information ([exhibits@arftg.org](mailto:exhibits@arftg.org)).

[www.arftg.org](http://www.arftg.org)





## ELECTRONIC SUBMISSION DEADLINES

**Electronic Abstract and Summary**

**September 10, 2010**

**Publication-Ready Paper in PDF Format**

**October 18, 2010**

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## ARFTG

### 76th Microwave Measurement Symposium **Millimeter-wave Measurements and Modeling**

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